

# Search Notes



Application/Control No.

10/694,295

Examiner

DANH C. LE

Applicant(s)/Patent under Reexamination

MAKI ET AL.

Art Unit

2683

## SEARCHED

Class	Subclass	Date	Examiner
455	439	8/1/05	DCL
	436		
	437		
370	332		
	331		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Inventor Name Search For double Patent check	8/1/05	DCL
EAST Search USP, US PUB		
EAST Search DERWENT, JPO, EPO	8/2/05	DCL
Interference Search		
Lee Nguyen (455)		
Hien Vuong (455)		